

Abstract

Systems increasingly depend on software

- Mission and life critical
- Must preserve high reliability and availability

Rush to deploy new technologies may result in

- Inadequate reliability testing
- Severe economic damage and loss of life

Recent National Academies report *Reliability Growth: Enhancing Defense System Reliability (2015)* recommends:

- "Use of reliability growth models to direct contractor design and test activities"

Contributions:

- **Free and open source tool for users**
<http://sasdlc.org/lab/projects/srt.html>
- **Collaborative environment for researchers**
- **Expectation conditional maximization (ECM) algorithms to ensure stability of convergence**

Goals and Objectives

Software Failure and Reliability Assessment Tool (SFRAT)

- Designed for practitioner and research community
- Programmed in R and provides functionality through Shiny graphical user interface
- Reduces the need for knowledge of the underlying statistical techniques
- Can help user quantitatively assess software as part of their data collection and reporting process

Allows users to answer following questions about a software system during test

1. Is software ready to release (Has it achieved a specified reliability goal)?
2. How much more time and test effort will be required to achieve a specified reliability goal?
3. What will be the consequences to a system's operational reliability if not enough testing resources are available?

Input Data Format

1. **Inter-failure (IF) times data:** Time between $(i - 1)^{st}$ and i^{th} failure, $t_i = (T_i - T_{i-1})$
2. **Failure times (FT) data:** Vector of failure times, $\mathbf{T} = \langle t_1, t_2, \dots, t_n \rangle$
3. **Failure count data:** Length of interval and number of failures observed within it, $\langle \mathbf{T}, \mathbf{K} \rangle = \langle (t_1, k_1), (t_2, k_2), \dots, (t_n, k_n) \rangle$

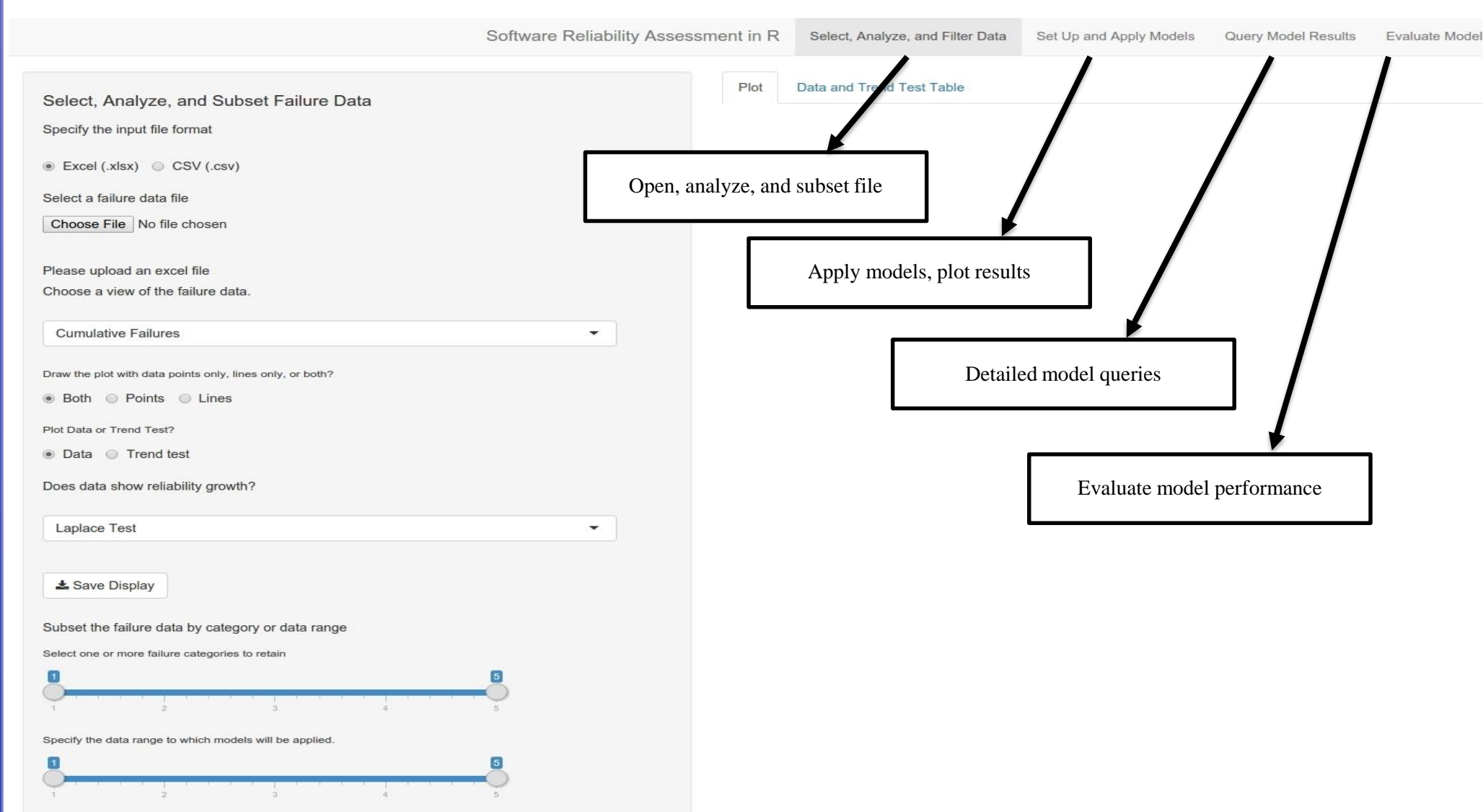
Input File format: Excel or CSV

1	FN	IF	FT
2		1	3
3		2	30
4		3	113
5		4	81
6		5	115
7

Output

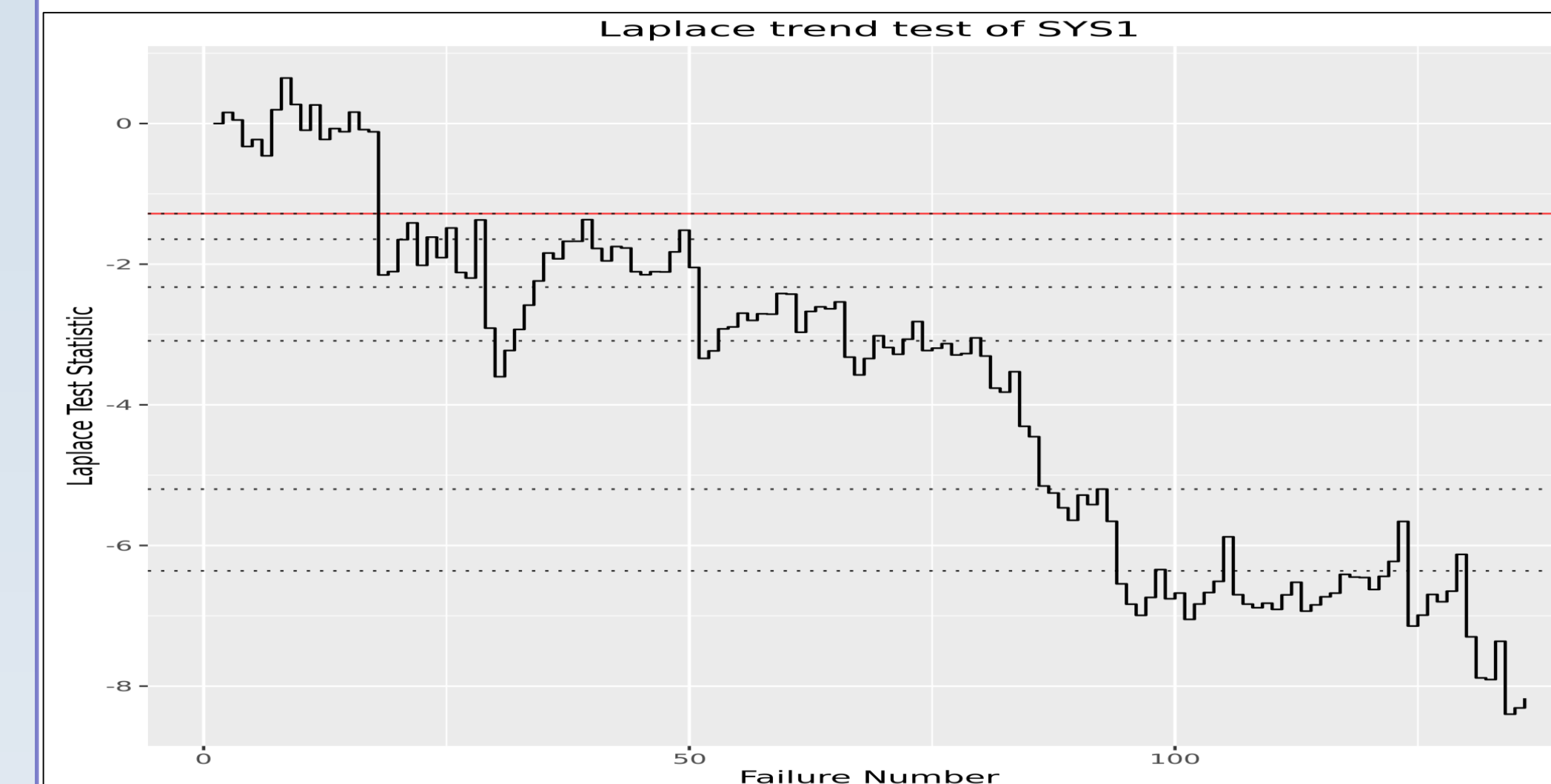
1. Trend tests (Assess if data exhibits reliability growth)
2. Model rankings (Select for prediction)
3. Visualization
 - Cumulative failure, time between failure, failure intensity, and reliability growth plots
4. Predictions
 - Time to achieve reliability
 - Expected number of faults for next t time units
 - Expected time to next k failures

SFRAT Tab view



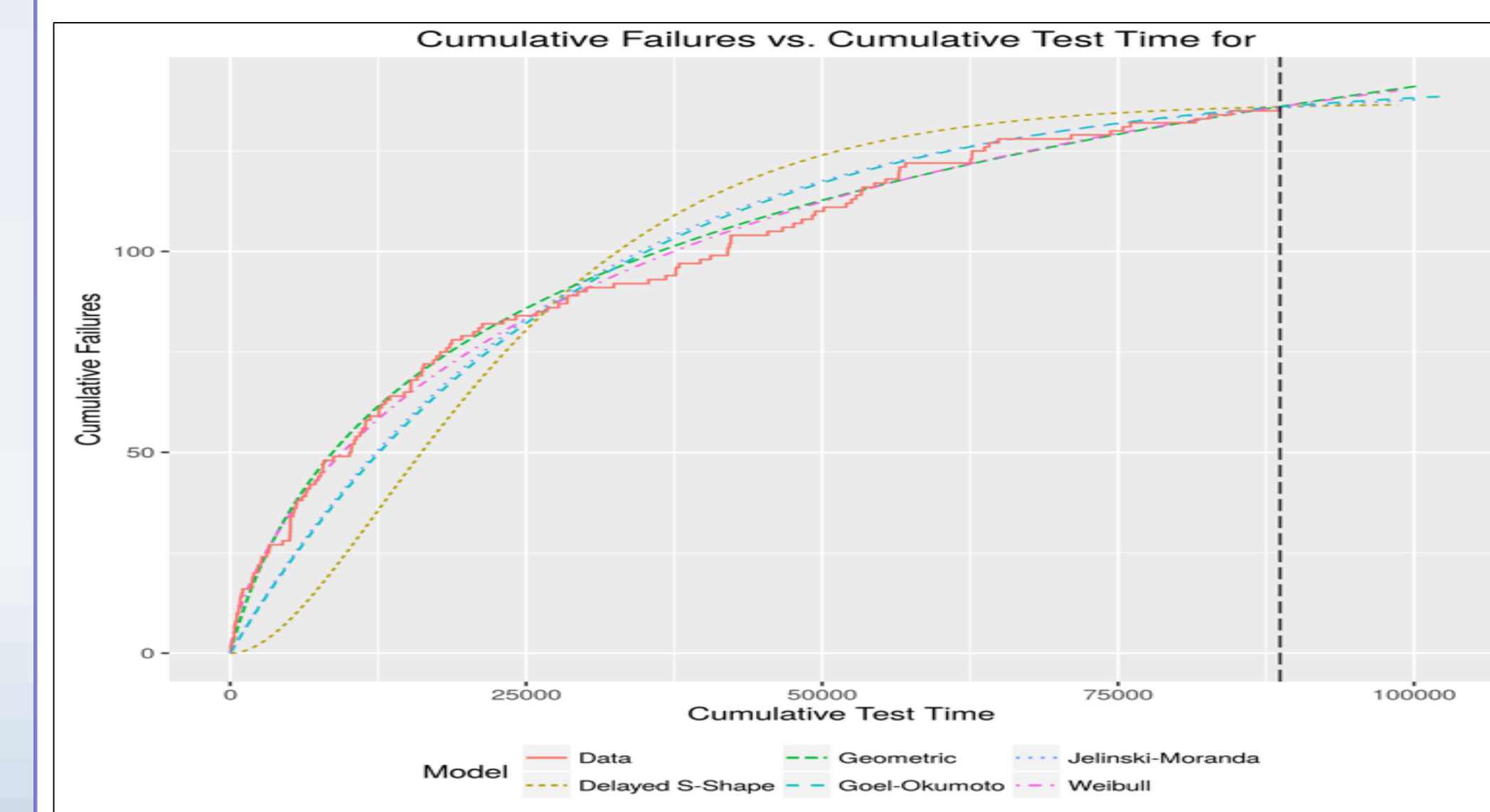
Tabs enable data input, visualization, model application, model query, and goodness of fit assessment.

Tab1: Laplace and Running arithmetic average



Decreasing trend indicates reliability growth. Red line indicates 90% confidence. Needed for model fitting algorithms to converge and predictions to be accurate.

Tab2: Model fit



Model fits (smooth lines) can be compared with data (red staircase plot). Predictions (beyond dotted black line).

Tab3: Predictions

Model	Time to achieve 90% reliability for mission of length 4116	Expected # of failures for next 4116 time units	Nth failure	Expected times to next 1 failures
Delayed S-shaped	12401.15	0.246856	1	N/A
Jelinski-Moranda	59915.29	0.856125	1	4869.807
Goel-Okumoto	62829.77	0.903615	1	4591.285
Weibull	259865.77	1.725954	1	2353.053
Geometric	1592716.46	1.877473	1	2170.031

Tab 4: Model assessment

Model	AIC	PSSE
Delayed S-shaped	2075.146	296.34925
Geometric	1937.034	84.32708
Goel-Okumoto	1953.613	23.07129
Jelinski-Moranda	1950.534	19.60037
Weibull	1938.161	74.94496

Models with lower AIC (Akaike information criterion) and PSSE (predictive sum of squares error) preferred.

Conclusions and Future Work

- Conclusions
 - Free and open source tool to promote collaboration
 - Application architecture enables integration of models and measures from research literature
 - ECM algorithms to improve stability of model fitting
- Future research
 - Expand architecture to encompass additional stages of software development lifecycle
 - Explore applications to system level assurance of cyber security
 - Multi-stage model fitting algorithms to improve speed and stability of convergence

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